Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/718,321	BAILLY ET AL.	
Examiner	Art Unit	
Yunsoo Kim	1644	

SEARCHED						
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Class	Subclass	Date	Examiner			
530	387.1	1/13/2005	YK			
435	326	1/13/2005	YK			
424	130.1	1/13/2005	YK			
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
SEQ ID NO:1 from stic	1/13/2005	YK	
inventor search in PALM and NPL	1/13/2005	YK	
domestic prioirity considered 60/295907 6/3/2001	1/13/2005	YK	